

WPI

TI - Electron beam irradiation scanning method for polyethylene terephthalate container - involves performing deflection of electron beam after beam scanning by applying magnetic force

AB - JP11248895 NOVELTY - Electron beam is irradiated on a drink container (20) for sterilization. Magnetic force is applied to perform deflection of electron beam after beam scanning. DETAILED DESCRIPTION - An INDEPENDENT CLAIM is also included for the electron beam scanner.

- USE - For sterilization of polyethylene terephthalate container used to accommodate food, drinks.

- ADVANTAGE - Uniform scanning can be performed by carrying out deflection of electron beam and therefore uniform sterilization can be performed in each part of container. DESCRIPTION OF DRAWING(S) - The figure shows the schematic diagram of the beam scanning type electron beam scanner. (20) Drink container.

- (Dwg.1/9)

PN - JP11248895 A 19990917 DW199950 G21K5/04 009pp

PR - JP19980064407 19980227

PA - (MITO) MITSUBISHI JUKOGYO KK

MC - A05-E04E A11-C A11-C04E A12-P06 D09-B K08-X

DC - A23 A92 D22 K08 P34 Q31 V05

IC - A23L3/26 ;A61L2/08 ;B65B55/08 ;G21K5/04 ;H01J37/30

AN - 1999-583537 [50]

PAJ

TI - ELECTRON BEAM IRRADIATION METHOD AND ITS DEVICE

AB - PROBLEM TO BE SOLVED: To provide an electron beam irradiation method and its device capable of unifying the electron beam absorption dose at each part in radiation direction in the case attaining intended purposes such as sterilizing by repeatedly scanning an electron beam for irradiating an object such as foods and drink containers even with objects different in thickness.

- SOLUTION: In the case attaining intended purposes such as sterilizing by repeated beam-scanning and radiating electron beam in two or three dimensional directions to a solid shape object such as foods and drink bottles, the electron beam 8 to be emitted to the object is partly deflected by magnetic line of force by arranging magnets 19A and 19B for deflecting the electron beam at a specific position between radiation positions to the object from a beam scan device and adding the magnetic line of force to the scanned electron beam in the direction deflecting the electron beam 8 by the magnets.

PN - JP11248895 A 19990917

PD - 1999-09-17

ABD - 19991222

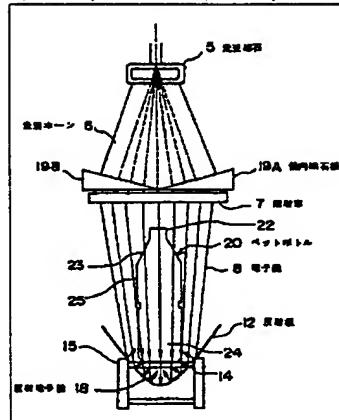
ABV - 199914

AP - JP19980064407 19980227

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I - G21K5/04 ;A23L3/26 ;A61L2/08 ;B65B55/08 ;H01J37/30



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